

## Supporting Information:

### **Full electrical control of multiple resistance states in van der Waals sliding multiferroic tunnel junctions**

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## Table of Contents

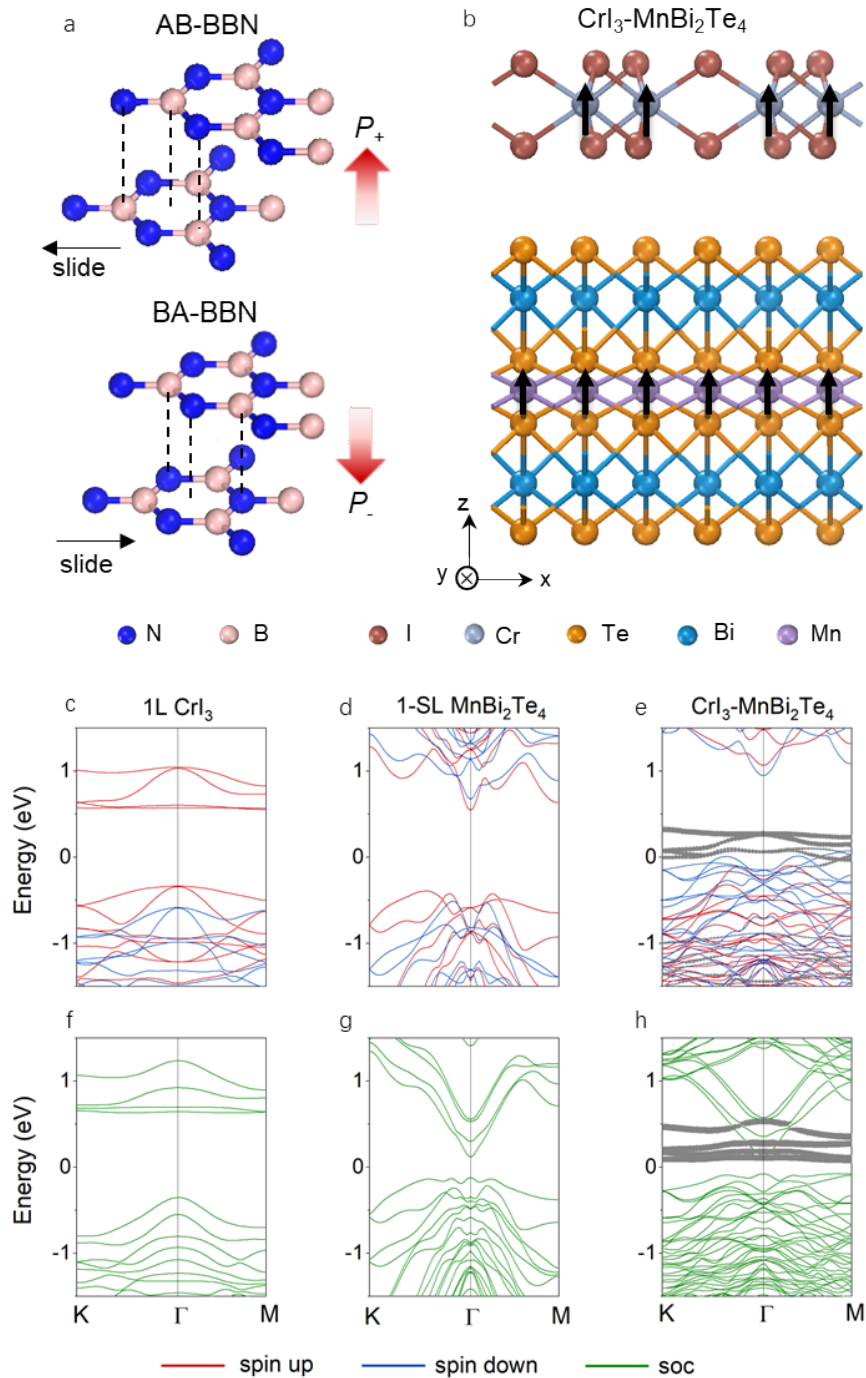
1. Geometric and electronic properties of BBN, CrI <sub>3</sub> , MnBi <sub>2</sub> Te <sub>4</sub> , and CrI <sub>3</sub>  MnBi <sub>2</sub> Te <sub>4</sub> .....	3
2. Ferroelectricity of the whole device.....	6
3. Spin-resolved device LDOS.....	7
4. Transmission spectra of MFTJs under different bias voltages .....	8
5. Parameters for spin transfer torque calculations .....	9
6. Outputs with SOC included under 0.4 V bias voltages .....	9
7. References.....	10

# 1. Geometric and electronic properties of BBN, CrI<sub>3</sub>, MnBi<sub>2</sub>Te<sub>4</sub>, and CrI<sub>3</sub>|MnBi<sub>2</sub>Te<sub>4</sub>

We start by revealing the electronic properties of the atomically thin BBN, CrI<sub>3</sub>, and MnBi<sub>2</sub>Te<sub>4</sub>, the framework of the vdW MFTJs. In the AB- (BA-) stack BBN (Fig.S1a), the more electronegative N atoms in the interlayer N-B pairs distort the  $2p_z$  orbital, generating vertical electric dipoles.<sup>1-2</sup> The AB and BA stacking orders as well as the polarization direction can be switched by sliding one-third of their unit cells. The magnetic moments in CrI<sub>3</sub> are aligned along the out-of-plane direction by I<sup>-</sup> ion-mediated Cr-Cr exchange coupling (Fig. S1b).<sup>3</sup> The calculated bandgaps of the FM 1L CrI<sub>3</sub> are 0.91 eV (3.01 eV) for the spin up (spin down) and 1.00 eV for spin-orbit coupling (SOC) (Figs. S1c and f). The AFM exchange coupling of bilayer CrI<sub>3</sub> is 2.13 meV (2.34 meV) per unit cell without (with) SOC (Table S1). Multilayer MnBi<sub>2</sub>Te<sub>4</sub> has intrinsic A-type out-of-plane AFM order. The AFM exchange coupling for two-septuple layer (2-SL) MnBi<sub>2</sub>Te<sub>4</sub> is calculated as 8.50 eV (6.26 eV) in  $\sqrt{3} \times \sqrt{3}$  supercell without (with) SOC (Table S1). Whereas the 1-SL MnBi<sub>2</sub>Te<sub>4</sub> is a FM semiconductor with a calculated bandgap of 0.93 eV (1.18 eV) for the spin up (spin down) channel, and 0.24 eV after considering SOC (Figs. S1d and g).<sup>4-5</sup>

The heterostructure of 1L CrI<sub>3</sub> on 1-SL MnBi<sub>2</sub>Te<sub>4</sub> forms very strong FM coupling. The CrI<sub>3</sub>-MBT heterostructure in Fig. S1b is made up of a unit cell of 1L CrI<sub>3</sub> and a  $\sqrt{3} \times \sqrt{3}$  supercell of 1-SL MnBi<sub>2</sub>Te<sub>4</sub> with a mismatch of 7%.<sup>5</sup> The optimized interlayer distance is 2.96 Å. The energy difference  $\Delta E$  between the FM and AFM orders of CrI<sub>3</sub>-MBT is -35.84 meV, which is consistent with previous results.<sup>5</sup> Such strong FM pinning is larger than the interlayer exchange coupling of bilayer CrI<sub>3</sub> (2.13 meV) and 2-SL MnBi<sub>2</sub>Te<sub>4</sub> (8.50 meV) with the same lattice dimension used in the heterostructure. This FM pinning strength is barely affected by the SOC ( $\Delta E = -34.18$  meV).

Notably, the 100% spin-polarized conduction bands around 0.6 eV (Fig. S1c) in the 1L CrI<sub>3</sub> are downwards shifted to (around) the Fermi level in Fig. S1e (h), exhibiting a half-metallic feature after contacting with the 1-SL MnBi<sub>2</sub>Te<sub>4</sub>. The half-metallic character implies a high spin screening efficiency and thus a high TMR performance when made into devices. The half-metallicity of the 1L CrI<sub>3</sub> is caused by the electron drift from the higher Fermi level of 1-SL MnBi<sub>2</sub>Te<sub>4</sub> (work function  $W_f = 5.65$  eV) to the lower one of 1L CrI<sub>3</sub> ( $W_f = 8.22$  eV) after contacting. The  $W_f$  of the CrI<sub>3</sub>-MBT heterostructure is 5.77 eV, very close to that of the 1-SL MnBi<sub>2</sub>Te<sub>4</sub>. This band alignment is again verified in MFTJs transport calculations, which are discussed in main text.

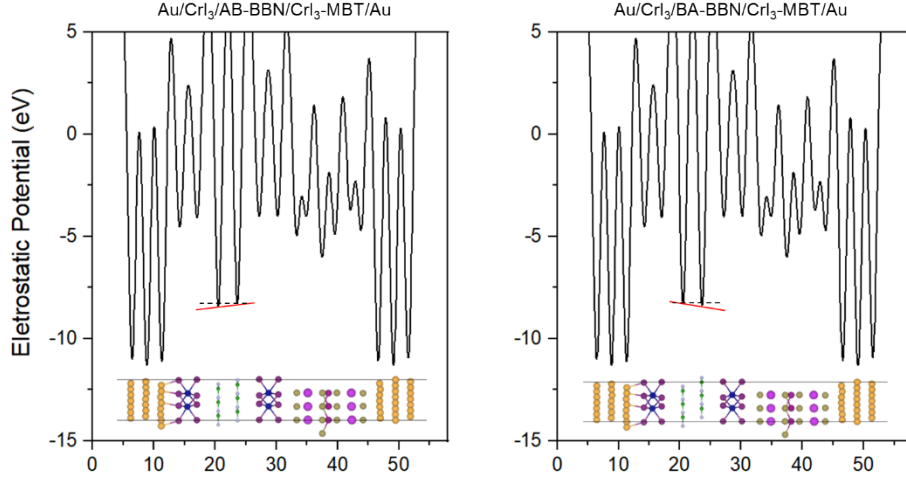


**Fig. S1 Geometric and electronic structures of 2D ferroic materials in MFTJs.** (a) Atomic arrangement of AB- and BA-stack bilayer *h*-BN (BBN). Ferroelectric polarization is labeled by the upward or downward red arrow. Sliding along the black arrow direction switches the ferroelectricity. (b) Side atomic view and ground magnetic state (black arrows) of the  $\text{CrI}_3\text{-MnBi}_2\text{Te}_4$  ( $\text{CrI}_3\text{-MBT}$ ) heterostructure. Spin-resolved band structures for 1 L  $\text{CrI}_3$ , 1-SL  $\text{MnBi}_2\text{Te}_4$ , and  $\text{CrI}_3\text{-MBT}$  heterostructure are shown in (c-e), respectively. (f-h) The same with (c-e) but includes spin-orbit coupling. The gray dots in (e) and (h) are projected Cr atoms. The Fermi level is set to zero.

**Table S1** Total energy difference  $\Delta E$  between the ferromagnetic and antiferromagnetic configurations for bilayer (BL)  $\text{CrI}_3$ , 2-SL  $\text{MnBi}_2\text{Te}_4$ , and the interface of monolayer  $\text{CrI}_3$  on 1-SL  $\text{MnBi}_2\text{Te}_4$ . Results with and without spin-orbit coupling (SOC) are shown.

		BL $\text{CrI}_3$ ( $1 \times 1$ )	2-SL $\text{MnBi}_2\text{Te}_4$ ( $\sqrt{3} \times \sqrt{3}$ )	$\text{CrI}_3$ - $\text{MnBi}_2\text{Te}_4$ ( $1 \times 1$ )/( $\sqrt{3} \times \sqrt{3}$ )
$\Delta E = E_{\text{FM}} - E_{\text{AFM}}$ (meV)	w/o SOC	2.13	8.50	-35.84
	SOC	2.34	6.26	-34.18

## 2. Ferroelectricity of the whole device



**Fig. S2** Planar averaged electrostatic potential of Au/CrI<sub>3</sub>/BBN/CrI<sub>3</sub>-MnBi<sub>2</sub>Te<sub>4</sub>/Au with AB- and BA-stacked configurations of BBN. The red lines connect the potentials of two BN layers.

Theoretically, once the energy provided by the electric field exceeds the sliding barrier (0.6 eV) based on our calculation, the polarization of BBN would be reversed. We can not directly calculate the specific threshold voltage that induces the BBN to finish sliding. Therefore, we make a rough approximation using the formula of energy density  $\omega$  of the statistic electric field  $E$ :

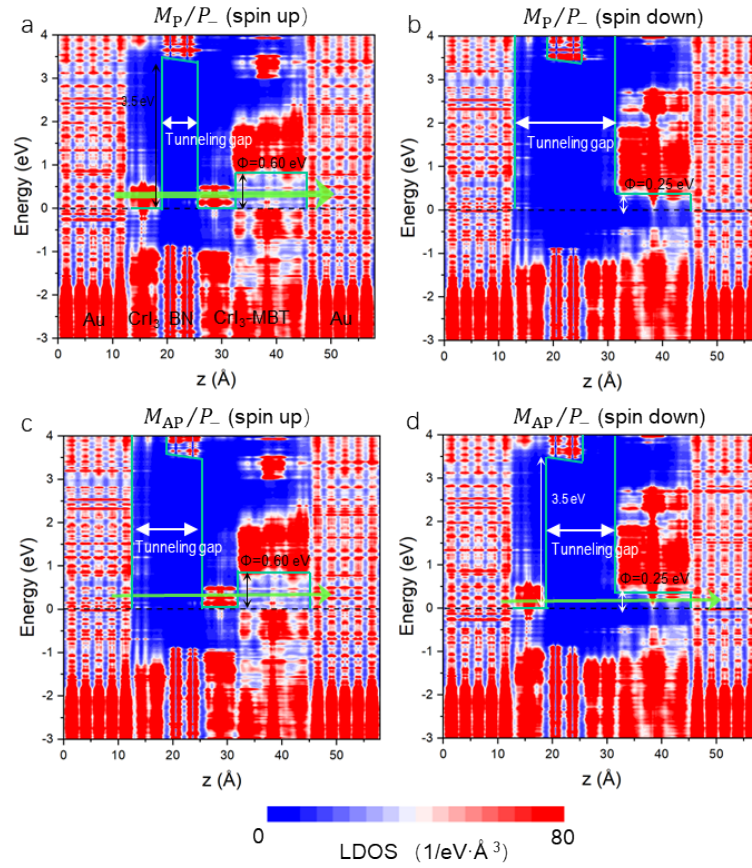
$$\omega = \frac{\epsilon_0}{2} E^2,$$

where  $\epsilon_0$ , the vacuum dielectric constant, is  $8.85 \times 10^{-12}$  F/m. In our MFTJ,

$$\omega = \frac{0.6 \text{ eV} \times 1.6 \times 10^{-19}}{7.55 \text{ nm} \times 7.55 \text{ nm} \times 5 \text{ nm}} = 0.34 \times 10^9 \text{ J/m}^3,$$

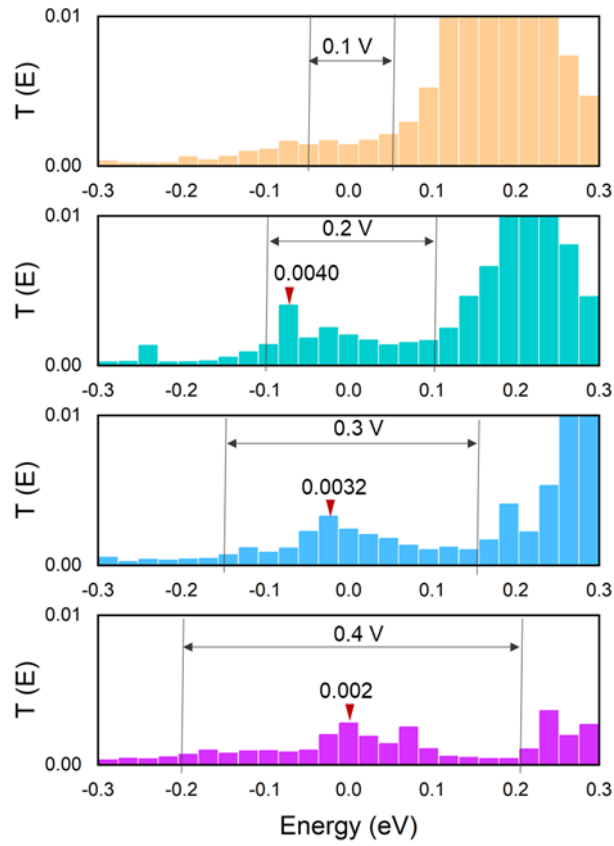
and the electric field  $E$  is then given by 0.8 V/nm. This approximation strongly relies on the calculated device size. In this regard, we believe that referring to the experimental polarization-switching electric field is more convincing.

### 3. Spin-resolved device LDOS



**Fig. S3** Spin-resolved local density of states (LDOS) of the Au/CrI<sub>3</sub>/BA-BBN/CrI<sub>3</sub>-MnBi<sub>2</sub>Te<sub>4</sub>/Au MFTJ with the (a-b) parallel magnetization alignment of two CrI<sub>3</sub> layers and (c-d) the antiparallel alignment. Two vertical green lines profile tunneling barriers. Green arrows indicate the tunneling direction in the device. The Fermi level refers to zero, marked by black dashed lines.

#### 4. Transmission spectra of MFTJs under different bias voltages



**Fig. S4** Transmission spectra of the Au/CrI<sub>3</sub>/AB-BBN/CrI<sub>3</sub>-MnBi<sub>2</sub>Te<sub>4</sub>/Au MFTJs under bias of 0.1, 0.2, 0.3, and 0.4 V, respectively, in the  $M_P$  state. Red triangles mark the main contribution to the current within the bias window.



## 5. Parameters for spin transfer torque calculations

**Table S2** Summary of the theoretical parameters for spin transfer torque calculation in the Au/CrI<sub>3</sub>/BBN/CrI<sub>3</sub>-MnBi<sub>2</sub>Te<sub>4</sub>/Au MFTJ.  $\alpha$  is the Gilbert damping factor,  $E_{\text{MAE}}$  the magnetic anisotropy energy,  $S$  the sectional area of the device,  $T_{\text{st-z}}$  the z component of spin transfer torque,  $V_c$  critical voltage for magnetization reversal,  $G$  the conductance,  $I_c$  the critical current for magnetization. All these parameters are obtained when the angle ( $\theta$ ) between two magnetic moments in the free and the pinned layers is 90°.

$\alpha$	$E_{\text{MAE}}$ (meV)	$S$ (Å <sup>2</sup> )	$T_{\text{st-z}}$ (eV/V)	$V_c$ (V)	$G$ ( $e^2/h$ )	$I_c$ (10 <sup>10</sup> A/m <sup>2</sup> )
0.01	3.60	49.39	$1.71 \times 10^{-4}$	0.21	$9.27 \times 10^{-4}$	1.53

## 6. Outputs with SOC included under 0.4 V bias voltages

**Table S3** The calculated current, TMR, and TER of the MFTJs at 0.4 voltage ( $V_b = 0.4$  V) with SOC.

$V_b$ (V)		$M_P$ state ( $\uparrow\uparrow$ )	$M_{AP}$ state ( $\uparrow\downarrow$ )	TMR
0.4	$I_{P+}$ (AB-BBN) (A)	$4.1 \times 10^{-8}$	$5.5 \times 10^{-9}$	640%
	$I_{P-}$ (BA-BBN) (A)	$3.7 \times 10^{-8}$	$4.3 \times 10^{-9}$	749%
	<b>TER</b>	11%	26%	

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